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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/645,603	FUJII, TATSUYA	
Examiner	Art Unit	
Shawn Riley	2838	

SEARCHED			
Class	Subclass	Date	Examiner
323	268	12/5/2005	SR
	269 272		
	updated	6/1/2006	SR

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
323	268			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
<u> </u>	DATE	EXMR	
interference search history attached	6/1/2006	SR	